



ELSEVIER

Applied Surface Science 99 (1996) 422-425

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## Author index

- Al-Wazzan, R.A., J.M. Hendron and T. Morrow, Line shape study of Ba ions in laser produced plasmas 99 (1996) 345
- Amoddeo, A., see Chiarello, G. 99 (1996) 15
- Aouadi, M.S., P.C. Wong and K.A.R. Mitchell, XPS study of carbon/inconel bilayers as a function of substrate bias 99 (1996) 319
- Arai, M., M. Fukushima and Y. Nishiyama, Interrupted-temperature programmed desorption of hydrogen over silica-supported platinum catalysts: the distribution of activation energy of desorption and the phenomena of spillover and reverse spillover of hydrogen 99 (1996) 145
- Asikainen, T., M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer, AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO thin films deposited by atomic layer epitaxy 99 (1996) 91
- Atamny, F., see Grunwaldt, J.-D. 99 (1996) 353
- Aubel, D., L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont, X-ray photoelectron diffraction investigation of Ge segregation and film morphology during first stage heteroepitaxy of Si on Ge(001) 99 (1996) 169
- Augereau, F., B. Cros and J.P. Marco, Surface study of cross-linking gradients in photopolymers by acoustic microscopy 99 (1996) 293
- Baiker, A., see Grunwaldt, J.-D. 99 (1996) 353
- Bancroft, G.M., see Kasrai, M. 99 (1996) 303
- Banerjee, S., M.K. Sanyal and A. Datta, A simulation study of multi-atom tips and estimation of resolution in atomic force microscopy 99 (1996) 255
- Baraldi, A., L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei, CO adsorption and CO oxidation on Rh(100) 99 (1996) 1
- Barberi, R., see Chiarello, G. 99 (1996) 15
- Bardwell, J.A., see Kasrai, M. 99 (1996) 303
- Barthés-Labrousse, M.G., see Marsh, J. 99 (1996) 335
- Bayrachny, B.I., see Skatkov, L.I. 99 (1996) 367
- Behner, H. and R. Rupp, Surface composition of CVD-grown  $\alpha$ -SiC layers - an XPS and LEED study 99 (1996) 27
- Bertrand, P., see Weng, L.T. 99 (1996) 185
- Bischoff, J.L., see Aubel, D. 99 (1996) 169
- Björkqvist, M., see Janin, E. 99 (1996) 371
- Bolmont, D., see Aubel, D. 99 (1996) 169
- Breza, J., see Liday, J. 99 (1996) 9
- Brunner, R.W., see Kasrai, M. 99 (1996) 303
- Caputi, L.S., see Chiarello, G. 99 (1996) 15
- Cassuto, A., see Colin, L. 99 (1996) 245
- Cauich, W., see Quintana, P. 99 (1996) 325
- Chadwick, D., J. McAleese, K. Senkiw and B.C.H. Steele, On the application of XPS to ceria films grown by MOCVD using a fluorinated precursor 99 (1996) 417
- Chen, Y., see Ji, W. 99 (1996) 151
- Cheremskoy, P.G., see Skatkov, L.I. 99 (1996) 367
- Chiarello, G., R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita, XPS and AFM characterization of a vanadium oxide film on  $\text{TiO}_2(100)$  surface 99 (1996) 15
- Chiou, B.-S., see Wu, W.-F. 99 (1996) 237
- Colavita, E., see Chiarello, G. 99 (1996) 15
- Colin, L., A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D. Jamois, Adsorption and decomposition of hexamethyldisiloxane on platinum: an XPS, UPS and TDS study 99 (1996) 245
- Comelli, G., see Baraldi, A. 99 (1996) 1
- Crisafulli, C., S. Scirè, S. Minicò, R. Maggioro and S. Galvagno, Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy 99 (1996) 401
- Cros, B., see Augereau, F. 99 (1996) 293
- Czanderna, A.W., see Jung, D.R. 99 (1996) 161
- Datta, A., see Banerjee, S. 99 (1996) 255
- Deslandes, Y., see Spevack, P. 99 (1996) 41
- Devillers, M., see Weng, L.T. 99 (1996) 185
- Dhanak, V.R., see Baraldi, A. 99 (1996) 1
- Ehrhardt, J.J., see Colin, L. 99 (1996) 245
- Feng, Z.C., see Li, K. 99 (1996) 59
- Flodström, A.S., see Hirschauer, B. 99 (1996) 285
- Friedbacher, G., see Asikainen, T. 99 (1996) 91

- Fukushima, M., see Arai, M. 99 (1996) 145  
 Fusy, J., see Ruby, C. 99 (1996) 393
- Galvagno, S., see Crisafulli, C. 99 (1996) 401  
 Gerlach, J.W., see Wengenmair, H. 99 (1996) 313  
 Geus, J.W., see Van Wijk, R. 99 (1996) 127  
 Geus, J.W., see Van Wijk, R. 99 (1996) 197  
 Gijzeman, O.L.J., see Van Wijk, R. 99 (1996) 127  
 Gijzeman, O.L.J., see Mens, A.J.M. 99 (1996) 133  
 Gijzeman, O.L.J., see Van Wijk, R. 99 (1996) 197  
 Göbel, U., see Grunwaldt, J.-D. 99 (1996) 353  
 Goldmann, A., see Kürpick, U. 99 (1996) 221  
 Gomošov, V.P., see Skatkov, L.I. 99 (1996) 367  
 Gorse, D., see Marsh, J. 99 (1996) 335  
 Görts, P.C., see Van Wijk, R. 99 (1996) 127  
 Göthelid, M., see Janin, E. 99 (1996) 371  
 Grasserbauer, M., see Asikainen, T. 99 (1996) 91  
 Gregoratti, L., see Baraldi, A. 99 (1996) 1  
 Grehk, T.M., see Janin, E. 99 (1996) 371  
 Grunwaldt, J.-D., F. Atamny, U. Göbel and A. Baiker, Preparation of thin silver films on mica studied by XRD and AFM 99 (1996) 353  
 Gui, L., see Guo, Q. 99 (1996) 229  
 Guo, Q., L. Gui and N. Wu, CuCl growth on the reconstructed surface of (0001) haematite 99 (1996) 229
- Habraken, F.H.P.M., see Van Wijk, R. 99 (1996) 127  
 Habraken, F.H.P.M., see Van Wijk, R. 99 (1996) 197  
 Hallin, C., see Marinova, Ts. 99 (1996) 119  
 Hendron, J.M., see Al-Wazzan, R.A. 99 (1996) 345  
 Hirschauer, B., S. Söderholm, J. Paul and A.S. Flodström, Large area synthesis of thin alumina films by laser ablation 99 (1996) 285
- Jamois, D., see Colin, L. 99 (1996) 245  
 Janin, E., M. Björkqvist, T.M. Grehk, M. Göthelid, C.-M. Pradier, U.O. Karlsson and A. Rosengren, Hydrogen adsorption on the Pt(111)( $\sqrt{3} \times \sqrt{3}$ )R30°-Sn surface alloy studied by high resolution core level photoelectron spectroscopy 99 (1996) 371  
 Jancén, E., see Marinova, Ts. 99 (1996) 119  
 Ji, W., Y. Chen, S. Shen, S. Li and H. Wang, FTIR study of adsorption of CO, NO and C<sub>2</sub>H<sub>4</sub> and reaction of CO + H<sub>2</sub> on the well-dispersed FeOx/ $\gamma$ -Al<sub>2</sub>O<sub>3</sub> and FeOx/TiO<sub>2</sub>(a) catalysts 99 (1996) 151  
 Jung, D.R. and A.W. Czanderna, X-ray photoelectron spectroscopy of Cr/COOCH<sub>3</sub> interfaces on self-assembled monolayers of 16-mercaptohexadecanoate 99 (1996) 161
- Karlsson, U.O., see Janin, E. 99 (1996) 371  
 Kasrai, M., W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan, Sampling depth of total electron and fluorescence measurements in Si L- and K-edge absorption spectroscopy 99 (1996) 303  
 Kawakami, E., see Oku, T. 99 (1996) 265  
 Kawakyu, Y., see Nishibe, T. 99 (1996) 35  
 Keller, B.A., see Osman, M.A. 99 (1996) 261  
 Kiskinova, M., see Baraldi, A. 99 (1996) 1  
 Knotter, D.M., Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions 99 (1996) 99  
 Koch, T. and P. Ziemann, Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature 99 (1996) 51  
 Krastev, V., see Marinova, Ts. 99 (1996) 119  
 Kubler, L., see Aubel, D. 99 (1996) 169  
 Kunimori, K., see Watanabe, K. 99 (1996) 411  
 Kürpick, U., G. Meister and A. Goldmann, Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study 99 (1996) 221
- Laidani, N., A. Miotello and J. Perrière, Chemical, mechanical and electrical properties of CN<sub>x</sub>-films produced by reactive sputtering and N<sup>+</sup>-implantation in carbon films 99 (1996) 273  
 Lennard, W.N., see Kasrai, M. 99 (1996) 303  
 Leskelä, M., see Asikainen, T. 99 (1996) 91  
 Li, K., J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb, Surface and interface analysis of GaSb/GaAs semiconductor materials 99 (1996) 59  
 Li, S., see Ji, W. 99 (1996) 151  
 Liday, J., S. Tomek and J. Breza, AES of semi-insulating polycrystalline silicon layers 99 (1996) 9  
 Lin, J., see Li, K. 99 (1996) 59  
 Linares-Solano, A., see Muñoz-Guillena, M.J. 99 (1996) 111
- Maggiore, R., see Crisafulli, C. 99 (1996) 401  
 Marco, J.P., see Augereau, F. 99 (1996) 293  
 Marée, C.H.M., see Van Wijk, R. 99 (1996) 127  
 Marée, C.H.M., see Van Wijk, R. 99 (1996) 197  
 Marinova, Ts., V. Krastev, C. Hallin, R. Yakimova and E. Jancén, Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC 99 (1996) 119  
 Marsh, J., L. Minel, M.G. Barthés-Labrousse and D. Gorse, The nature of the surface acidity of anodised titanium: an XPS study using 1,2-diaminoethane 99 (1996) 335  
 Matsuura, Y., see Nishibe, T. 99 (1996) 35  
 McAleese, J., see Chadwick, D. 99 (1996) 417  
 Meister, G., see Kürpick, U. 99 (1996) 221  
 Mens, A.J.M. and O.L.J. Gijzeman, AES study of electron beam induced damage on TiO<sub>2</sub> surfaces 99 (1996) 133

- Minel, L., see Marsh, J. 99 (1996) 335
- Minicò, S., see Crisafulli, C. 99 (1996) 401
- Miotello, A., see Laidani, N. 99 (1996) 273
- Mitchell, K.A.R., see Aouadi, M.S. 99 (1996) 319
- Mitsuhashi, H., see Nishibe, T. 99 (1996) 35
- Morrow, T., see Al-Wazzan, R.A. 99 (1996) 345
- Muñoz-Guillena, M.J., A. Linares-Solano and C. Salinas-Martínez de Lecea, High temperature SO<sub>2</sub> retention by CaO 99 (1996) 111
- Murakami, M., see Oku, T. 99 (1996) 265
- Nishibe, T., H. Mitsuhashi, Y. Matsuura and Y. Kawakyu, Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser 99 (1996) 35
- Nishigaki, S., see Yamada, K. 99 (1996) 21
- Nishiyama, Y., see Arai, M. 99 (1996) 145
- Norton, P.R., see Zhdanov, V.P. 99 (1996) 205
- Ohnuma, H., see Watanabe, K. 99 (1996) 411
- Oku, T., E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami, Diffusion barrier property of TaN between Si and Cu 99 (1996) 265
- Osman, M.A. and B.A. Keller, Wettability of native silver surfaces 99 (1996) 261
- Pastuszka, S., A.S. Terekhov and A. Wolf, 'Stable to unstable' transition in the (Cs, O) activation layer on GaAs (100) surfaces with negative electron affinity in extremely high vacuum 99 (1996) 361
- Paul, J., see Hirschauer, B. 99 (1996) 285
- Pedraza, F., see Vázquez, A. 99 (1996) 213
- Peña, J.L., see Quintana, P. 99 (1996) 325
- Pere, J., see Valden, M. 99 (1996) 83
- Perrière, J., see Laidani, N. 99 (1996) 273
- Pessa, M., see Valden, M. 99 (1996) 83
- Pomes, R., see Quintana, P. 99 (1996) 325
- Pradier, C.-M., see Janin, E. 99 (1996) 371
- Preckwinkel, U., see Wengenmair, H. 99 (1996) 313
- Prohaska, T., see Asikainen, T. 99 (1996) 91
- Quintana, P., L. Veleva, W. Cauch, R. Pomes and J.L. Peña, Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico 99 (1996) 325
- Rauschenbach, B., see Wengenmair, H. 99 (1996) 313
- Reniers, F., E. Silberberg, N. Roose and J. Vereecken, Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles 99 (1996) 379
- Ritala, M., see Asikainen, T. 99 (1996) 91
- Roose, N., see Reniers, F. 99 (1996) 379
- Rosei, R., see Baraldi, A. 99 (1996) 1
- Rosengren, A., see Janin, E. 99 (1996) 371
- Ruby, C. and J. Fusy, Oxidation of ultrathin iron layers grown on Cu(111) 99 (1996) 393
- Ruiz-Lopez, M.F., see Colin, L. 99 (1996) 245
- Rupp, R., see Behner, H. 99 (1996) 27
- Salinas-Martínez de Lecea, C., see Muñoz-Guillena, M.J. 99 (1996) 111
- Sanyal, M.K., see Banerjee, S. 99 (1996) 255
- Scirè, S., see Crisafulli, C. 99 (1996) 401
- Senkiw, K., see Chadwick, D. 99 (1996) 417
- Shen, S., see Ji, W. 99 (1996) 151
- Silberberg, E., see Reniers, F. 99 (1996) 379
- Simon, L., see Aubel, D. 99 (1996) 169
- Skatkov, L.I., P.G. Cheremskoy, V.P. Gomo-zov and B.I. Bayrachny, Investigation of the solid surface structural inhomogeneities by the 'combined' small-angle X-ray scattering and Hg porosimetry methods 99 (1996) 367
- Söderholm, S., see Hirschauer, B. 99 (1996) 285
- Spevack, P. and Y. Deslandes, ToF-SIMS analysis of adsorbate/membrane interactions. I. Adsorption of dehydroabietic acid on poly(vinylidene fluoride) 99 (1996) 41
- Steele, B.C.H., see Chadwick, D. 99 (1996) 417
- Stritzker, B., see Wengenmair, H. 99 (1996) 313
- Takahiro, K., see Oku, T. 99 (1996) 265
- Tan, K.H., see Kasrai, M. 99 (1996) 303
- Tan, K.L., see Li, K. 99 (1996) 59
- Terekhov, A.S., see Pastuszka, S. 99 (1996) 361
- Tirions, O., see Weng, L.T. 99 (1996) 185
- Tomek, S., see Liday, J. 99 (1996) 9
- Tomellini, M., Modelling of the particle size distribution function in the nucleation and early stages of thin film growth 99 (1996) 67
- Uekubo, M., see Oku, T. 99 (1996) 265
- Uetsuka, H., see Watanabe, K. 99 (1996) 411
- Valden, M., N. Xiang, J. Pere and M. Pessa, Dissociative chemisorption of methane on clean and oxygen precovered Pt(111) 99 (1996) 83
- Van Wijk, R., P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus, The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry 99 (1996) 127
- Van Wijk, R., C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus, <sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100) 99 (1996) 197
- Vázquez, A. and F. Pedraza, High resolution electron microscopy characteriza-

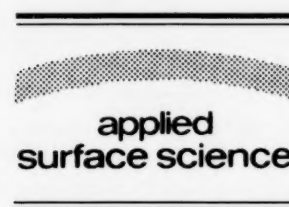


- tion of small Pt-Pd/SiO<sub>2</sub> particles in  
oxide-reducing cycles 99 (1996) 213
- Veleva, L., see Quintana, P. 99 (1996) 325
- Vereecken, J., see Reniers, F. 99 (1996) 379
- Wang, H., see Ji, W. 99 (1996) 151
- Watanabe, K., H. Uetsuka, H. Ohnuma and  
K. Kunimori, Infrared chemilumines-  
cence study of the dynamics of catalytic  
oxidation of CO and HCOOH on  
Pd(111) and polycrystalline Pd surfaces 99 (1996) 411
- Webb, J.B., see Li, K. 99 (1996) 59
- Wee, A.T.S., see Li, K. 99 (1996) 59
- Weng, L.T., P. Bertrand, O. Tirions and M.  
Devillers, Time-of-flight SIMS study of  
Bi-Mo selective oxidation catalysts 99 (1996) 185
- Wengenmair, H., J.W. Gerlach, U. Preck-  
winkel, B. Stritzker and B. Rauschen-  
bach, Photon and ion beam assisted de-  
position of titanium nitride 99 (1996) 313
- Wolf, A., see Pastuszka, S. 99 (1996) 361
- Wong, P.C., see Aouadi, M.S. 99 (1996) 319
- Wu, N., see Guo, Q. 99 (1996) 229
- Wu, W.-F. and B.-S. Chiou, Properties of  
radio frequency magnetron sputtered sil-  
icon dioxide films 99 (1996) 237
- Xiang, N., see Valden, M. 99 (1996) 83
- Yakimova, R., see Marinova, Ts. 99 (1996) 119
- Yamada, K. and S. Nishigaki, Oxidation of  
a Si(001) surface mediated by repetitive  
adsorption/desorption cycles of Cs: a  
metastable deexcitation spectroscopy  
study 99 (1996) 21
- Yamaguchi, S., see Oku, T. 99 (1996) 265
- Zhdanov, V.P. and P.R. Norton, Growth of  
oxide films on metal surfaces: transition  
from parabolic to linear kinetics 99 (1996) 205
- Ziemann, P., see Koch, T. 99 (1996) 51



ELSEVIER

Applied Surface Science 99 (1996) 426-436



## Subject index

### *Ablation*

- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285

### *Alkali metals*

- Oxidation of a Si(001) surface mediated by repetitive adsorption/desorption cycles of Cs: a metastable deexcitation spectroscopy study, K. Yamada and S. Nishigaki 99 (1996) 21

### *Alloys*

- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- Hydrogen adsorption on the Pt(111)( $\sqrt{3} \times \sqrt{3}$ )R30°-Sn surface alloy studied by high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist, T.M. Grehk, M. Göthelid, C.-M. Pradier, U.O. Karlsson and A. Rosengren 99 (1996) 371

### *Aluminium oxide*

- Modelling of the particle size distribution function in the nucleation and early stages of thin film growth, M. Tomellini 99 (1996) 67
- FTIR study of adsorption of CO, NO and C<sub>2</sub>H<sub>4</sub> and reaction of CO + H<sub>2</sub> on the well-dispersed FeOx/ $\gamma$ -Al<sub>2</sub>O<sub>3</sub> and FeOx/TiO<sub>2</sub>(a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang 99 (1996) 151
- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285

### *Annealing*

- Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mitsuhashi, Y. Matsuura and Y. Kawakyu 99 (1996) 35

### *Atomic force microscopy*

- XPS and AFM characterization of a vanadium oxide film on TiO<sub>2</sub>(100) surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15
- Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mitsuhashi, Y. Matsuura and Y. Kawakyu 99 (1996) 35
- AFM and STM studies on In<sub>2</sub>O<sub>3</sub> and ITO thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer 99 (1996) 91
- A simulation study of multi-atom tips and estimation of resolution in atomic force microscopy, S. Banerjee, M.K. Sanyal and A. Datta 99 (1996) 255
- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353

### *Auger electron spectroscopy*

- AES of semi-insulating polycrystalline silicon layers, J. Liday, S. Tomek and J. Breza 99 (1996) 9
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- Surface and interface analysis of GaSb/GaAs semiconductor materials, K. Li, J.

- Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb 99 (1996) 59
- AES study of electron beam induced damage on  $\text{TiO}_2$  surfaces, A.J.M. Mens and O.L.J. Gijzeman 99 (1996) 133
- $^{18}\text{O}$ -exchange with the substrate during  $^{18}\text{O}$  oxidation of Cu particles supported on  $^{16}\text{O}$ -oxidised  $\text{Si}(100)$ , R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229
- Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken 99 (1996) 379
- Oxidation of ultrathin iron layers grown on  $\text{Cu}(111)$ , C. Ruby and J. Fusy 99 (1996) 393
- ### Bismuth
- Time-of-flight SIMS study of Bi-Mo selective oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers 99 (1996) 185
- ### Carbides
- Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken 99 (1996) 379
- ### Carbon
- Chemical, mechanical and electrical properties of  $\text{CN}_x$ -films produced by reactive sputtering and  $\text{N}^+$ -implantation in carbon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- ### Carbon monoxide
- CO adsorption and CO oxidation on  $\text{Rh}(100)$ , A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- FTIR study of adsorption of CO, NO and  $\text{C}_2\text{H}_4$  and reaction of  $\text{CO} + \text{H}_2$  on the well-dispersed  $\text{FeOx}/\gamma\text{-Al}_2\text{O}_3$  and  $\text{FeOx}/\text{TiO}_2(\text{a})$  catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang 99 (1996) 151
- Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno 99 (1996) 401
- Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and  $\text{HCOOH}$  on  $\text{Pd}(111)$  and polycrystalline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411
- ### Catalysis
- High resolution electron microscopy characterization of small Pt-Pd/ $\text{SiO}_2$  particles in oxide-reducing cycles, A. Vázquez and F. Pedraza 99 (1996) 213
- Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno 99 (1996) 401
- Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and  $\text{HCOOH}$  on  $\text{Pd}(111)$  and polycrystalline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411
- ### Chemical vapour deposition
- Surface composition of CVD-grown  $\alpha\text{-SiC}$  layers – an XPS and LEED study, H. Behner and R. Rupp 99 (1996) 27
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- On the application of XPS to ceria films grown by MOCVD using a fluorinated precursor, D. Chadwick, J. McAleese, K. Senkiw and B.C.H. Steele 99 (1996) 417
- ### Chromium
- X-ray photoelectron spectroscopy of  $\text{Cr}/\text{COOCH}_3$  interfaces on self-assembled monolayers of 16-mercaptohexadecanoate, D.R. Jung and A.W. Czanderna 99 (1996) 161
- Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken 99 (1996) 379

*Copper*

The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus

99 (1996) 127

<sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus

99 (1996) 197

Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann

99 (1996) 221

CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu

99 (1996) 229

Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami

99 (1996) 265

Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy

99 (1996) 393

Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno

99 (1996) 401

*Corrosion*

Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña

99 (1996) 325

*Depth profiling*

Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken

99 (1996) 379

*Electrical properties*

Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. Yakimova and E. Janzén

99 (1996) 119

'Stable to unstable' transition in the (Cs, O) activation layer on GaAs (100) surfaces

with negative electron affinity in extremely high vacuum, S. Pastuszka, A.S. Terekhov and A. Wolf

99 (1996) 361

*Electron diffraction*

Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy

99 (1996) 393

*Electron energy loss spectroscopy*

CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu

99 (1996) 229

*Electron microscopy*

Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter

99 (1996) 99

High resolution electron microscopy characterization of small Pt-Pd/SiO<sub>2</sub> particles in oxide-reducing cycles, A. Vázquez and F. Pedraza

99 (1996) 213

Properties of radio frequency magnetron sputtered silicon dioxide films, W.-F. Wu and B.-S. Chiou

99 (1996) 237

Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami

99 (1996) 265

Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach

99 (1996) 313

Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña

99 (1996) 325

*Electron stimulated desorption*

AES study of electron beam induced damage on TiO<sub>2</sub> surfaces, A.J.M. Mens and O.L.J. Gijzeman

99 (1996) 133

*Ellipsometry*

The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée,



O.L.J. Gijzeman, F.H.P.M. Habraken  
and J.W. Geus

99 (1996) 127

### Epitaxy

Zr-silicide formation during the epitaxial  
growth of Y-stabilized zirconia films on  
Si(100) and its avoidance by ion beam  
assisted deposition at a reduced temper-  
ature, T. Koch and P. Ziemann

99 (1996) 51

AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO  
thin films deposited by atomic layer epi-  
taxy, T. Asikainen, M. Ritala, M.  
Leskelä, T. Prohaska, G. Friedbacher  
and M. Grasserbauer

99 (1996) 91

X-ray photoelectron diffraction investiga-  
tion of Ge segregation and film mor-  
phology during first stage heteroepitaxy  
of Si on Ge(001), D. Aubel, L. Kubler,  
J.L. Bischoff, L. Simon and D. Bolmont

99 (1996) 169

### Evaporation

Photon and ion beam assisted deposition of  
titanium nitride, H. Wengenmair, J.W.  
Gerlach, U. Preckwinkel, B. Stritzker  
and B. Rauschenbach

99 (1996) 313

Preparation of thin silver films on mica  
studied by XRD and AFM, J.-D. Grun-  
waldt, F. Atamny, U. Göbel and A.  
Baiker

99 (1996) 353

### Gallium antimonide

Surface and interface analysis of GaSb/  
GaAs semiconductor materials, K. Li, J.  
Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng  
and J.B. Webb

99 (1996) 59

### Gallium arsenide

Surface and interface analysis of GaSb/  
GaAs semiconductor materials, K. Li, J.  
Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng  
and J.B. Webb

99 (1996) 59

'Stable to unstable' transition in the (Cs, O)  
activation layer on GaAs (100) surfaces  
with negative electron affinity in ex-  
tremely high vacuum, S. Pastuszka, A.S.  
Terekhov and A. Wolf

99 (1996) 361

### Germanium

X-ray photoelectron diffraction investiga-  
tion of Ge segregation and film mor-

phology during first stage heteroepitaxy  
of Si on Ge(001), D. Aubel, L. Kubler,  
J.L. Bischoff, L. Simon and D. Bolmont

99 (1996) 169

### Halogenides

CuCl growth on the reconstructed surface of  
(0001) haematite, Q. Guo, L. Gui and  
N. Wu

99 (1996) 229

### Hydrocarbons

X-ray photoelectron spectroscopy of Cr/  
 $\text{COOCH}_3$  interfaces on self-assembled  
monolayers of 16-mercaptohexade-  
canoate, D.R. Jung and A.W. Czanderna

99 (1996) 161

### Hydrogen

Interrupted-temperature programmed de-  
sorption of hydrogen over silica-sup-  
ported platinum catalysts: the distribu-  
tion of activation energy of desorption  
and the phenomena of spillover and re-  
verse spillover of hydrogen, M. Arai, M.  
Fukushima and Y. Nishiyama

99 (1996) 145

Hydrogen adsorption on the  $\text{Pt}(111)(\sqrt{3} \times \sqrt{3})\text{R}30^\circ\text{-Sn}$  surface alloy studied by  
high resolution core level photoelectron  
spectroscopy, E. Janin, M. Björkqvist,  
T.M. Grehk, M. Göthelid, C.-M. Pradier,  
U.O. Karlsson and A. Rosengren

99 (1996) 371

### Indium

AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO  
thin films deposited by atomic layer epi-  
taxy, T. Asikainen, M. Ritala, M.  
Leskelä, T. Prohaska, G. Friedbacher  
and M. Grasserbauer

99 (1996) 91

### Infrared spectroscopy

FTIR study of adsorption of CO, NO and  
 $\text{C}_2\text{H}_4$  and reaction of  $\text{CO} + \text{H}_2$  on the  
well-dispersed  $\text{FeOx}/\gamma\text{-Al}_2\text{O}_3$  and  
 $\text{FeOx}/\text{TiO}_2(\text{a})$  catalysts, W. Ji, Y. Chen,  
S. Shen, S. Li and H. Wang

99 (1996) 151

FTIR study of adsorption of CO, NO and  
 $\text{C}_2\text{H}_4$  and reaction of  $\text{CO} + \text{H}_2$  on the  
well-dispersed  $\text{FeOx}/\gamma\text{-Al}_2\text{O}_3$  and  
 $\text{FeOx}/\text{TiO}_2(\text{a})$  catalysts, W. Ji, Y. Chen,  
S. Shen, S. Li and H. Wang

99 (1996) 151

Properties of radio frequency magnetron  
sputtered silicon dioxide films, W.-F.  
Wu and B.-S. Chiou

99 (1996) 237



- Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno 99 (1996) 401
- Interfaces*
- Surface and interface analysis of GaSb/GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb 99 (1996) 59
- Ion bombardment*
- Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach 99 (1996) 313
- Ion implantation*
- Chemical, mechanical and electrical properties of CN<sub>x</sub>-films produced by reactive sputtering and N<sup>+</sup>-implantation in carbon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273
- Ion scattering*
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- <sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197
- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami 99 (1996) 265
- Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach 99 (1996) 313
- Iron*
- FTIR study of adsorption of CO, NO and C<sub>2</sub>H<sub>4</sub> and reaction of CO + H<sub>2</sub> on the well-dispersed FeOx/γ-Al<sub>2</sub>O<sub>3</sub> and FeOx/TiO<sub>2</sub>(a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang 99 (1996) 151
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy 99 (1996) 393
- Laser processing*
- Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mitsushashi, Y. Matsuura and Y. Kawakyu 99 (1996) 35
- Line shape study of Ba ions in laser produced plasmas, R.A. Al-Wazzan, J.M. Hendron and T. Morrow 99 (1996) 345
- Low energy electron diffraction*
- CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- Surface composition of CVD-grown α-SiC layers—an XPS and LEED study, H. Behner and R. Rupp 99 (1996) 27
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229
- Luminescence*
- Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and HCOOH on Pd(111) and polycrystalline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411
- Metals*
- Growth of oxide films on metal surfaces: transition from parabolic to linear kinetics, V.P. Zhdanov and P.R. Norton 99 (1996) 205
- Methane*
- Dissociative chemisorption of methane on clean and oxygen precovered Pt(111), M. Valden, N. Xiang, J. Pere and M. Pessa 99 (1996) 83

*Mica*

- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353

*Molybdenum*

- Time-of-flight SIMS study of Bi-Mo selective oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers 99 (1996) 185

*Multilayers*

- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319

*Nickel*

- Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. Yakimova and E. Janzén 99 (1996) 119
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319

*Nitrides*

- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami 99 (1996) 265
- Chemical, mechanical and electrical properties of CN<sub>x</sub>-films produced by reactive sputtering and N<sup>+</sup>-implantation in carbon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273

*Nuclear reaction analysis*

- The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 127
- <sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197

*Organic substances*

- X-ray photoelectron spectroscopy of Cr/COOCH<sub>3</sub> interfaces on self-assembled monolayers of 16-mercaptohexadecanoate, D.R. Jung and A.W. Czanderna 99 (1996) 161

*Oxidation*

- CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- Oxidation of a Si(001) surface mediated by repetitive adsorption/desorption cycles of Cs: a metastable deexcitation spectroscopy study, K. Yamada and S. Nishigaki 99 (1996) 21
- The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 127
- Time-of-flight SIMS study of Bi-Mo selective oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers 99 (1996) 185
- <sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197
- Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy 99 (1996) 393
- Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and HCOOH on Pd(111) and polycrystalline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411

*Oxides*

- XPS and AFM characterization of a vanadium oxide film on TiO<sub>2</sub>(100) surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15
- Growth of oxide films on metal surfaces: transition from parabolic to linear kinetics, V.P. Zhdanov and P.R. Norton 99 (1996) 205
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229

*Oxygen*

- Dissociative chemisorption of methane on clean and oxygen precovered Pt(111),

- M. Valden, N. Xiang, J. Pere and M. Pessa 99 (1996) 83
- Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann 99 (1996) 221
- 'Stable to unstable' transition in the (Cs, O) activation layer on GaAs (100) surfaces with negative electron affinity in extremely high vacuum, S. Pastuszka, A.S. Terekhov and A. Wolf 99 (1996) 361
- ### Palladium
- High resolution electron microscopy characterization of small Pt-Pd/SiO<sub>2</sub> particles in oxide-reducing cycles, A. Vázquez and F. Pedraza 99 (1996) 213
- Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and HCOOH on Pd(111) and polycrystalline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411
- ### Photoelectron spectroscopy
- CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- XPS and AFM characterization of a vanadium oxide film on TiO<sub>2</sub>(100) surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15
- Surface composition of CVD-grown  $\alpha$ -SiC layers - an XPS and LEED study, H. Behner and R. Rupp 99 (1996) 27
- Surface and interface analysis of GaSb/GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb 99 (1996) 59
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. Yakimova and E. Janzén 99 (1996) 119
- X-ray photoelectron spectroscopy of Cr/COOCH<sub>3</sub> interfaces on self-assembled monolayers of 16-mercaptohexadecanoate, D.R. Jung and A.W. Czanderna 99 (1996) 161
- X-ray photoelectron diffraction investigation of Ge segregation and film morphology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont 99 (1996) 169
- <sup>18</sup>O-exchange with the substrate during <sup>18</sup>O oxidation of Cu particles supported on <sup>16</sup>O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197
- Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann 99 (1996) 221
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229
- Adsorption and decomposition of hexamethyldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D. Jamois 99 (1996) 245
- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- The nature of the surface acidity of anodised titanium: an XPS study using 1,2-diaminoethane, J. Marsh, L. Minel, M.G. Barthés-Labrousse and D. Gorse 99 (1996) 335
- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353
- On the application of XPS to ceria films grown by MOCVD using a fluorinated precursor, D. Chadwick, J. McAleese, K. Senkiw and B.C.H. Steele 99 (1996) 417
- ### Platinum
- Modelling of the particle size distribution function in the nucleation and early stages of thin film growth, M. Tomellini 99 (1996) 67
- Dissociative chemisorption of methane on clean and oxygen precovered Pt(111), M. Valden, N. Xiang, J. Pere and M. Pessa 99 (1996) 83
- Interrupted-temperature programmed desorption of hydrogen over silica-supported platinum catalysts: the distribution of activation energy of desorption and the phenomena of spillover and reverse spillover of hydrogen, M. Arai, M. Fukushima and Y. Nishiyama 99 (1996) 145
- High resolution electron microscopy characterization of small Pt-Pd/SiO<sub>2</sub> particles in oxide-reducing cycles, A. Vázquez and F. Pedraza 99 (1996) 213



- Adsorption and decomposition of hexamethyldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D. Jamois 99 (1996) 245
- Hydrogen adsorption on the  $\text{Pt}(111)(\sqrt{3} \times \sqrt{3})\text{R}30^\circ\text{-Sn}$  surface alloy studied by high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist, T.M. Grehk, M. Göthelid, C.-M. Pradier, U.O. Karlsson and A. Rosengren 99 (1996) 371
- Polymers**
- Surface study of cross-linking gradients in photopolymers by acoustic microscopy, F. Augereau, B. Cros and J.P. Marco 99 (1996) 293
- Pulsed laser deposition**
- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285
- Line shape study of Ba ions in laser produced plasmas, R.A. Al-Wazzan, J.M. Hendron and T. Morrow 99 (1996) 345
- Rhodium**
- CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- Ruthenium**
- Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno 99 (1996) 401
- Scanning tunneling microscopy**
- AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer 99 (1996) 91
- Secondary ion mass spectrometry**
- ToF-SIMS analysis of adsorbate/membrane interactions. I. Adsorption of dehydroabietic acid on poly(vinylidene fluoride), P. Spevack and Y. Deslandes 99 (1996) 41
- Surface and interface analysis of GaSb/GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb 99 (1996) 59
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- Time-of-flight SIMS study of Bi-Mo selective oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers 99 (1996) 185
- Semiconductors**
- Surface and interface analysis of GaSb/GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb 99 (1996) 59
- Silicides**
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- Silicon**
- AES of semi-insulating polycrystalline silicon layers, J. Liday, S. Tomek and J. Breza 99 (1996) 9
- Oxidation of a Si(001) surface mediated by repetitive adsorption/desorption cycles of Cs: a metastable deexcitation spectroscopy study, K. Yamada and S. Nishigaki 99 (1996) 21
- Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mitsuhashi, Y. Matsuura and Y. Kawakyu 99 (1996) 35
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 127
- X-ray photoelectron diffraction investigation of Ge segregation and film morphology during first stage heteroepitaxy

- of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont 99 (1996) 169
- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami 99 (1996) 265
- Sampling depth of total electron and fluorescence measurements in Si L- and K-edge absorption spectroscopy, M. Kasrai, W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan 99 (1996) 303
- ### Silicon carbide
- Surface composition of CVD-grown  $\alpha$ -SiC layers - an XPS and LEED study, H. Behner and R. Rupp 99 (1996) 27
- Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. Yakimova and E. Janzén 99 (1996) 119
- ### Silicon oxide
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- $^{18}\text{O}$ -exchange with the substrate during  $^{18}\text{O}$  oxidation of Cu particles supported on  $^{16}\text{O}$ -oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197
- High resolution electron microscopy characterization of small Pt-Pd/SiO<sub>2</sub> particles in oxide-reducing cycles, A. Vázquez and F. Pedraza 99 (1996) 213
- Properties of radio frequency magnetron sputtered silicon dioxide films, W.-F. Wu and B.-S. Chiou 99 (1996) 237
- Sampling depth of total electron and fluorescence measurements in Si L- and K-edge absorption spectroscopy, M. Kasrai, W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan 99 (1996) 303
- ### Silver
- Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann 99 (1996) 221
- Wettability of native silver surfaces, M.A. Osman and B.A. Keller 99 (1996) 261
- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353
- ### Sputter deposition
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- Properties of radio frequency magnetron sputtered silicon dioxide films, W.-F. Wu and B.-S. Chiou 99 (1996) 237
- Chemical, mechanical and electrical properties of CN<sub>x</sub>-films produced by reactive sputtering and N<sup>+</sup>-implantation in carbon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- ### Sulphur dioxide
- High temperature SO<sub>2</sub> retention by CaO, M.J. Muñoz-Guillena, A. Linares-Solano and C. Salinas-Martínez de Lecea 99 (1996) 111
- ### Tantalum
- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami 99 (1996) 265
- ### Thermal desorption
- CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei 99 (1996) 1
- High temperature SO<sub>2</sub> retention by CaO, M.J. Muñoz-Guillena, A. Linares-Solano and C. Salinas-Martínez de Lecea 99 (1996) 111
- Interrupted-temperature programmed desorption of hydrogen over silica-supported platinum catalysts: the distribution of activation energy of desorption and the phenomena of spillover and reverse spillover of hydrogen, M. Arai, M. Fukushima and Y. Nishiyama 99 (1996) 145
- FTIR study of adsorption of CO, NO and C<sub>2</sub>H<sub>4</sub> and reaction of CO + H<sub>2</sub> on the well-dispersed FeOx/ $\gamma$ -Al<sub>2</sub>O<sub>3</sub> and FeOx/TiO<sub>2</sub>(a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang 99 (1996) 151

- Adsorption and decomposition of hexamethyldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D. Jamois 99 (1996) 245
- Thin films*
- Surface composition of CVD-grown  $\alpha$ -SiC layers – an XPS and LEED study, H. Behner and R. Rupp 99 (1996) 27
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- Modelling of the particle size distribution function in the nucleation and early stages of thin film growth, M. Tomellini 99 (1996) 67
- AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer 99 (1996) 91
- Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter 99 (1996) 99
- X-ray photoelectron diffraction investigation of Ge segregation and film morphology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont 99 (1996) 169
- Properties of radio frequency magnetron sputtered silicon dioxide films, W.-F. Wu and B.-S. Chiou 99 (1996) 237
- Chemical, mechanical and electrical properties of  $\text{CN}_x$ -films produced by reactive sputtering and  $\text{N}^+$ -implantation in carbon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273
- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285
- Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach 99 (1996) 313
- XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell 99 (1996) 319
- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353
- Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken 99 (1996) 379
- On the application of XPS to ceria films grown by MOCVD using a fluorinated precursor, D. Chadwick, J. McAleese, K. Senkiw and B.C.H. Steele 99 (1996) 417
- Time of flight techniques*
- ToF-SIMS analysis of adsorbate/membrane interactions. I. Adsorption of dehydroabiatic acid on poly(vinylidene fluoride), P. Spevack and Y. Deslandes 99 (1996) 41
- Time-of-flight SIMS study of Bi-Mo selective oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers 99 (1996) 185
- Tin*
- Hydrogen adsorption on the  $\text{Pt}(111)(\sqrt{3} \times \sqrt{3})\text{R}30^\circ\text{-Sn}$  surface alloy studied by high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist, T.M. Grehk, M. Göthelid, C.-M. Pradier, U.O. Karlsson and A. Rosengren 99 (1996) 371
- Tin oxide*
- AFM and STM studies on  $\text{In}_2\text{O}_3$  and ITO thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer 99 (1996) 91
- Titanium*
- The nature of the surface acidity of anodised titanium: an XPS study using 1,2-diaminoethane, J. Marsh, L. Minel, M.G. Barthés-Labrousse and D. Gorse 99 (1996) 335
- Titanium nitride*
- Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach 99 (1996) 313
- Titanium oxide*
- XPS and AFM characterization of a vanadium oxide film on  $\text{TiO}_2(100)$  surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15



- AES study of electron beam induced damage on  $\text{TiO}_2$  surfaces, A.J.M. Mens and O.L.J. Gijzeman 99 (1996) 133
- FTIR study of adsorption of CO, NO and  $\text{C}_2\text{H}_4$  and reaction of  $\text{CO} + \text{H}_2$  on the well-dispersed  $\text{FeOx}/\gamma\text{-Al}_2\text{O}_3$  and  $\text{FeOx}/\text{TiO}_2(\text{a})$  catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang 99 (1996) 151
- Tungsten**
- Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken 99 (1996) 379
- Vanadium**
- XPS and AFM characterization of a vanadium oxide film on  $\text{TiO}_2(100)$  surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15
- X-ray absorption**
- Sampling depth of total electron and fluorescence measurements in Si L- and K-edge absorption spectroscopy, M. Kasrai, W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan 99 (1996) 303
- X-ray diffraction**
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- X-ray photoelectron diffraction investigation of Ge segregation and film morphology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont 99 (1996) 169
- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami 99 (1996) 265
- Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström 99 (1996) 285
- Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach 99 (1996) 313
- Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña 99 (1996) 325
- Preparation of thin silver films on mica studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. Baiker 99 (1996) 353
- X-ray scattering**
- Investigation of the solid surface structural inhomogeneities by the 'combined' small-angle X-ray scattering and Hg porosimetry methods, L.I. Skatkov, P.G. Cheremskoy, V.P. Gomofov and B.I. Bayrachny 99 (1996) 367
- Yttrium**
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51
- Zinc**
- Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña 99 (1996) 325
- Zirconium**
- Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann 99 (1996) 51